SD7276.1/S100,326 February 4, 2004

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## IN THE U.S. PATENT AND TRADEMARK OFFICE

APPLICANTS:

Michael R. Keenan

SERIAL NO.:

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FILED:

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**EXAMINER:** 

FOR:

Spectral Compression Algorithms for the Analysis of Very Large

Multivariate Images

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

February 4, 2004

## INFORMATION DISCLOSURE STATEMENT

The following sections are being submitted for this Information Disclosure Statement:

1. Preliminary Statements

Applicants submit herewith patents, publications or other information of which they are aware, which they believe may be material to the examination of this application and in respect of which there may be a duty to disclose.

The filing of this Information Disclosure Statement shall not be construed as a representation that a search has been made (37 CFR 1.97(g)), an admission that the information cited is, or is considered to be, material to patentability or that no other material information exists.

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- 2. Form PTO 1449 (Modified).
- 3. The person making this statement is the attorney or agent who signs below on the basis of the information supplied by the inventor(s) and the information in the attorney's or agent's file.

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CERTIFICATE OF MAILING

I hereby certify that this paper (along with any referred to as being attached or enclosed) is being deposited with the U. S. Postal Service on the date shown below as Express Mail No. EV332388315US in an envelope addressed to the: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Martha Trujillo

Martha Trujillo

Form PTO-1449 (SNL-Modified) (2-91)

List of Patents and Publications

for Applicant's

Information Disclosure Statement

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(use several sheets if necessary)

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## REFERENCE DESIGNATION

Ex'r		Sub
Init	Document No.  Date  Name	Class Class   File Date
		Sub   Translation
	Document No.  Date  Name	Class Class   Yes   X No

- AA | 6,584,413 6/24/2003 Keenan et al.
- AB | 6,675,106 1/6/2004 Keenan et al

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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- |BB | Alsberg et al., "Speed improvement of multivariate algorithms by the method of postponed basis matrix multiplication Part I. Principal component analysis,"

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- |BC | Kiers et al., "Relating two proposed methods for speedup of algorithms for fitting two- and three-way principal component and related multilinear models," <a href="Chemometrics Intell. Lab. Syst">Chemometrics Intell. Lab. Syst</a>. 36, 31 (1997).
- |BD | Vogt et al., "Fast principal component analysis of large data sets," Chemometrics Intell. Lab. Syst. 59, 1 (2001).
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- |BI | Kotula et al., "Automated Analysis of SEM X-Ray Spectral Images: A Powerful New Microanalysis Tool," <u>Microscopy and Microanalysis 9</u>, 1 (2003).
- |BJ | Bro et al., "Improving the speed of multi-way algorithms: Part II: Compression," <u>Chemometrics Intell. Lab Syst.</u> 42, 105 (1998).

Examiner:	Date Considered: